NCME • 2008 Annual Meeting & Training Sessions

Wednesday, 12:25 p.m. – 1:55 p.m., Room 405 – 406, G4

Test-Taking Effort and Response Time - Paper Session

Moderator

Gale Roid, Southern Methodist University

Presenters

Shu-Ren Chang, Rockford Public Schools, IL, Barbara Plake, University of Nebraska, Lincoln, Shu-Mei Lien, University of Nebraska, Lincoln Development and Applications of Detection Indices for Measuring Guessing Behaviors and Test-Taking Effort in Computerized Adaptive Testing (CAT)

Siang Chee Chuah, American Institute of Certified Public Accountants, Wim van der Linden, University of Twente

Detection of Aberrant Candidate Responses: Improving Detection by Combining Response Pattern and Response Time Data

Patrick Meyer, James Madison University

A Mixture Rasch Model with Item Response Time Components

Steven Wise, James Madison University, Christine DeMars, James Madison University

The Impact of Examinee Non-Effort on the Validity of Assessment Test Data

Aaron Douglas, Mathematica Policy Research, Inc. An Investigation of How Restrictive Time Limits Affect the Fundamental Assumptions of Item Response Theory (IRT) Models

Discussant

Robert Smith, Educational Testing Service